



MICROCHIP

QUALIFICATION REPORT SUMMARY

PCN #: MFOL-13NKUY500

Date:

March 20, 2026

Qualification of MTAI as an additional final test site for AT27C512R-70PU, AT27C256R-45PU, AT27C256R-70PU, AT27C512R-45PU, AT27C4096-55PU, AT27C4096-90PU, AT27C020-90PU, AT27C040-70PU, AT27C040-90PU, AT27C080-90PU, AT27C010-70PU, AT27C020-55PU, AT27C040-90JU, AT27C080-90JU, AT27C040-70JU, AT27C040-70JU-T, AT27C040-90JU-T, AT27C080-90JU-T, AT27C010-45JU-T, AT27C010-45JU, AT27C010-70JU, AT27C010-70JU-T, AT27BV256-70JU, AT27LV256A-90JU, AT27BV256-70JU-T, AT27BV010-90JU-T, AT27C256R-70JU, AT27LV010A-70JU-T, AT27LV020A-12JU, AT27LV020A-12JU-T, AT27C256R-45JU, AT27C512R-70JU, AT27C256R-70JU-306, AT27C256R-45JU-T, AT27C256R-70JU-T, AT27C512R-45JU, AT27C020-55JU-T, AT27C512R-45JU-T, AT27C512R-70JU-T, AT27C020-55JU, AT27C020-90JU, AT27C020-90JU-T, AT27LV256A-90JU-T, AT27BV010-90JU, AT27LV010A-70JU, AT27LV512A-90JU, AT27LV512A-90JU-T, AT27C1024-45PU and AT27C1024-70PU catalog part numbers (CPN) available in various packages.

Purpose: Qualification of MTAI as an additional final test site for AT27C512R-70PU, AT27C256R-45PU, AT27C256R-70PU, AT27C512R-45PU, AT27C4096-55PU, AT27C4096-90PU, AT27C020-90PU, AT27C040-70PU, AT27C040-90PU, AT27C080-90PU, AT27C010-70PU, AT27C020-55PU, AT27C040-90JU, AT27C080-90JU, AT27C040-70JU, AT27C040-70JU-T, AT27C040-90JU-T, AT27C080-90JU-T, AT27C010-45JU-T, AT27C010-45JU, AT27C010-70JU, AT27C010-70JU-T, AT27BV256-70JU, AT27LV256A-90JU, AT27BV256-70JU-T, AT27BV010-90JU-T, AT27C256R-70JU, AT27LV010A-70JU-T, AT27LV020A-12JU, AT27LV020A-12JU-T, AT27C256R-45JU, AT27C512R-70JU, AT27C256R-70JU-306, AT27C256R-45JU-T, AT27C256R-70JU-T, AT27C512R-45JU, AT27C020-55JU-T, AT27C512R-45JU-T, AT27C512R-70JU-T, AT27C020-55JU, AT27C020-90JU, AT27C020-90JU-T, AT27LV256A-90JU-T, AT27BV010-90JU, AT27LV010A-70JU, AT27LV512A-90JU, AT27LV512A-90JU-T, AT27C1024-45PU and AT27C1024-70PU catalog part numbers (CPN) available in various packages.

CCB No.: 8018

Test Name	Test Conditions	Sample Size	Qty of Lots	Fail/Accept Criteria	Result
Bin and Yield Comparison	Test the same units at existing and destination locations and compare Bin and Yield data.	3000	1	≤0.1%	Pass
Parametric / Characterization Comparison	Characterize the same units at existing and destination locations and compare data.	33	1	≤10%	Pass
Correlation Lot Report	Yield at each step and reject analysis between systems. 33 units are tested as lot correlation Accept on yield match within 0.1%	33	1	≤0.1%	Pass